

AUTOMOTIVE CURRENT TRANSDUCER OPEN LOOP TECHNOLOGY HAH1BVW S/12





Introduction

The HAH1BVW family is for the electronic measurement of DC, AC or pulsed currents in high power and low voltage automotive applications with galvanic separation between the primary circuit (high power) and the secondary circuit (electronic circuit).

The HAH1BVW family gives you the choice of having different current measuring ranges in the same housing.

Features

- Ratiometric transducer
- · Open Loop transducer using the Hall effect
- · Low voltage application
- Unipolar +5 V DC power supply
- Primary current measuring range ±1200 A
- Maximum RMS primary admissible current: defined by busbar to have T° < +150 °C
- Operating temperature range: −40 °C < T° < 125 °C
- Output voltage: full ratio-metric (in sensitivity and offset).

Advantages

- Excellent accuracy
- Very good linearity
- · Very low thermal offset drift
- Very low thermal sensitivity drift
- Galvanic separation
- Non intrusive solution.

Automotive application

Battery Management.

Principle of HAH1BVW Family

The open loop transducers uses a Hall effect integrated circuit. The magnetic flux density B, contributing to the rise of the Hall voltage, is generated by the primary current $I_{\rm P}$ to be measured. The current to be measured $I_{\rm P}$ is supplied by a current source i.e. battery or generator (Figure 1).

Within the linear region of the hysteresis cycle, ${\it B}$ is proportional to:

 $B(I_p)$ = constant (a) × I_p

The hall voltage is thus expressed by:

 $V_{\rm H}$ = (Hall coefficient / d) × I × constant (a) × $I_{\rm P}$

With d = thickness of the hall plates

I =current accross the Hall plates

Except for $I_{\rm p}$, all terms of this equation are constant. Therefore:

$$V_{\rm H}$$
 = constant (b) × $I_{\rm P}$

The measurement signal $V_{\rm H}$ amplified to supply the user output voltage or current.

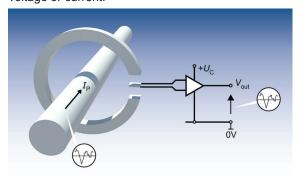
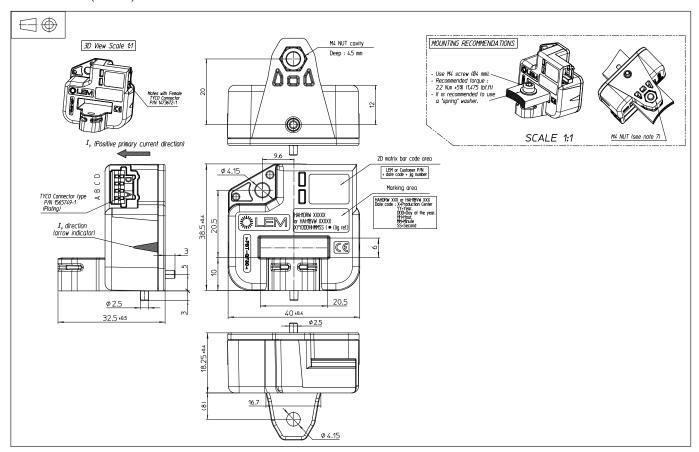


Fig. 1: Principle of the open loop transducer



Dimensions (in mm)



Mechanical characteristics

Plastic case PBT GF30

Magnetic core
 FeSi alloy

Mass 57 g ±5 % g

Pins
 Brass tin plated

IP level IPx2.

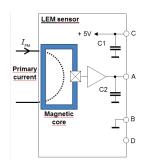
Mounting recommendation

Mating connector type
 TYCO connector P/N 1473672-1

Assembly torque max
 2.2 N·m ±5 %

Soldering type
 N/A

Electronic schematic



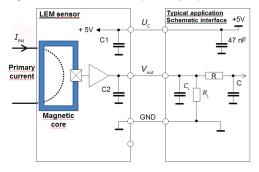
	Components list						
IC	Hall sensor ASIC						
C1	Decoupling capacitor 100 nF						
C2	EMC protection capacitor	68 nF					

	Pin out					
Α	V _{out}					
В	GND					
С	U _C (5 V)					
D	not connected					

Remark

 V_{out} > V_o when I_P flows in the positive direction (see arrow on drawing).

System architecture (example)



C_L< 100 nF EMC protection (optional) RC Low pass filter (optional)

On board diagnostic

 $R_{\rm I}$ > 10 K Ω . Resistor for signal line diagnostic (optional)

V _{out}	Diagnostic
Open circuit	V _{IN} ≤ 0.15 V
Short GND	V _{IN} ≤ 0.15 V



Absolute ratings (not operating)

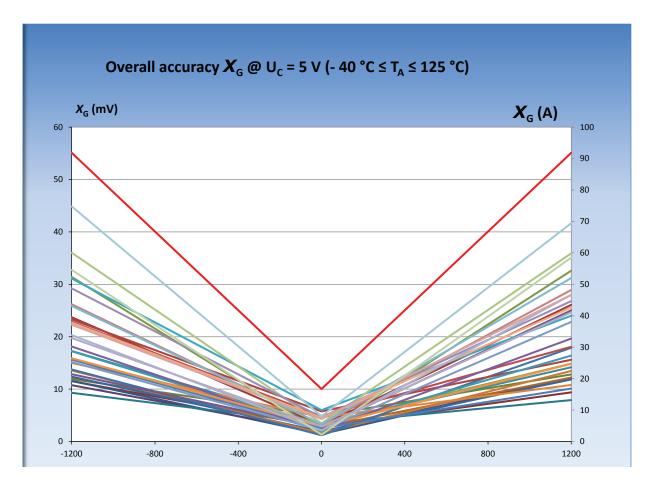
Parameter	Symbol	Unit	Specification			Conditions
Faranietei	Syllibol		Min	Typical	Max	Conditions
Maximum supply voltage	U _c	V			14	
Maximum reverse supply voltage	U _c	V	-14			
Maximum output Voltage	V _{out}	V	-14		14	V _{out} Reverse / Forward voltage
Maximum output Current	$I_{ m out}$	mA	-10		10	
Ambient storage temperature	T _s	°C	-40		125	
Electrostatic discharge voltage (HBM)	U _{ESD}	kV			8	
Maximum admissible vibration (random rms)	γ	m·s⁻²			96.6	10 to 2000 Hz, −40 °C to 125 °C
Rms voltage for AC insulation test	U _d	kV			2	50 Hz, 1 min
Creepage distance	d _{Cp}	mm	5.2			
Clearance	d _{CI}	mm	4.9			
Comparative traking index	CTI			PLC3		

Operating characteristics in nominal range ($I_{\rm PN}\!)$

Parameter	Symbol	Unit	Specification		tion	Conditions	
r ai ailietei			Min	Typical	Max	Conditions	
Electrical Data							
Primary current, measuring range	$I_{\scriptscriptstyle{PM}}$	Α	-1200		1200		
Primary nominal rms current	$I_{_{\mathrm{PN}}}$	Α	-1200		1200		
Supply voltage	U _c	V	4.5	5	5.5		
Ambient operating temperature	T _A	°C	-40		125		
Output voltage	V _{out}	V	V _{out} = (1	$U_{\rm c}/5) \times (V_{\rm o}$	$+ G \times I_{P}$)		
Sensitivity	G	mV/A		1.67		@ T _A = 25 °C	
Offset voltage	V _o	V		2.5			
Output resolution		mV		2.5			
Output clamping high voltage	V _{sz}		4.74			@ U _c = 5 V	
Output clamping low voltage	V _{sz}				0.26	@ U _c = 5 V	
Comment and the second	7			7		@ $T_A = 25 ^{\circ}\text{C}$, @ $U_C = 5 ^{\circ}\text{V}$	
Current consumption	$I_{\scriptscriptstyle m C}$	mA			10		
Load resistance	$R_{\scriptscriptstyle L}$	ΚΩ	10				
O to Catalog and a catalog and	_			1		@ T _A = 25 °C	
Output internal resistance	R _{out}	Ω			10		
		Perfo	rmance	Data	•		
Ratiometricity error	ε,	%		±0.2			
Sensitivity error	ε _G	%		±1		@ T _A = 25 °C, @ U _C = 5 V	
Electrical offset voltage	V _{OE}	mV		±2.5		@ $T_A = 25 ^{\circ}\text{C}$, @ $U_C = 5 ^{\circ}\text{V}$	
Magnetic offset voltage	V _{om}	mV		±2		@ U _C = 5 V, @ T _A = 25 °C	
Linearity error	\mathcal{E}_{L}	%	-1		1	% of full scale	
Average temperature coefficient of V_{OE}	TCV _{OE AV}	mV/°C		±0.06		@ U _c = 5 V	
Average temperature coefficient of G	TCG _{AV}	%/°C		±0.02			
Step response time @ 70 %	t,	ms			10		
Frequency bandwidth	BW	Hz		70		@ -3 dB	
Output voltage noise peak-peak	V _{no pp}	mV			10	DC to 1 MHz	
Output rms noise voltage	V _{no}	mV			1.6		
Start up time	t _{start}	ms			1		
Setting time after overload	t _s	ms			10		



Overall accuracy $X_{\rm G}$

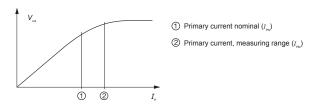


	Overall accuracy $oldsymbol{X}_{ ext{G}}$ specification. Max value @ \pm 3 σ						
I_{P} (A)	T _A=	: 25 °C, U _c =	5 V	- 25 °C ≤ T _A ≤125 °C, U _c =5 V			
-1200	25 mV	14.97 A	1.25 %	55 mV	32.93 A	2.75 %	
0	7 mV	4.19 A	0.35 %	10 mV	5.99 A	0.50 %	
1200	25 mV	14.97 A	1.25 %	55 mV	32.93 A	2.75 %	



PERFORMANCES PARAMETERS DEFINITIONS

Primary current definition:



Definition of typical, minimum and maximum values:

Minimum and maximum values for specified limiting and safety conditions have to be understood as such as values shown in "typical" graphs. On the other hand, measured values are part of a statistical distribution that can be specified by an interval with upper and lower limits and a probability for measured values to lie within this interval. Unless otherwise stated (e.g. "100 % tested"), the LEM definition for such intervals designated with "min" and "max" is that the probability for values of samples to lie in this interval is 99.73 %. For a normal (Gaussian) distribution, this corresponds to an interval between -3 sigma and +3 sigma. If "typical" values are not obviously mean or average values, those values are defined to delimit intervals with a probability of 68.27 %, corresponding to an interval between -sigma and +sigma for a normal distribution. Typical, minimum and maximum values are determined during the initial characterization of a product.

Output noise voltage:

The output voltage noise is the result of the noise floor of the Hall elements and the linear amplifier.

Magnetic offset:

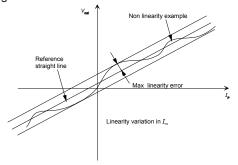
The magnetic offset is the consequence of an over-current on the primary side. It's defined after an excursion of $I_{\scriptscriptstyle \mathrm{PN}}$.

Linearity:

The maximum positive or negative discrepancy with a reference straight line $V_{\rm out} = f(I_{\rm P})$. Unit: linearity (%) expressed with full scale of $I_{\rm PN}$.

Response time (delay time) t_{\cdot} :

The time between the primary current signal $(I_{\rm PN})$ and the output signal reach at 90 % of its final value.

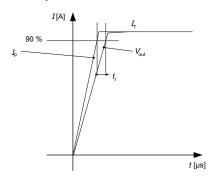


Sensitivity:

The transducer's sensitivity *G* is the slope of the straight line $V_{\text{out}} = f(I_{\text{p}})$, it must establish the relation:

$$V_{\text{out}}(I_{\text{P}}) = U_{\text{C}}/5 (G \times I_{\text{P}} + V_{\text{o}})$$

Offset with temperature:



The error of the offset in the operating temperature is the variation of the offset in the temperature considered with the initial offset at 25 °C.

The offset variation $I_{\scriptscriptstyle OT}$ is a maximum variation the offset in the temperature range:

$$I_{\mbox{\tiny OT}}$$
 = $I_{\mbox{\tiny OE}}$ max - $I_{\mbox{\tiny OE}}$ min

The offset drift TCI_{OFAV} is the I_{OT} value divided by the temperature range.

Sensitivity with temperature:

The error of the sensitivity in the operating temperature is the relative variation of sensitivity with the temperature considered with the initial offset at 25 °C.

The sensitivity variation G_{τ} is the maximum variation (in ppm or %) of the sensitivity in the temperature range:

 G_{τ} = (Sensitivity max – Sensitivity min) / Sensitivity at 25 °C. The sensitivity drift TCG_{AV} is the G_T value divided by the temperature range. Deeper and detailed info available is our LEM technical sales offices (www.lem.com).

Offset voltage @ I_p = 0 A:

The offset voltage is the output voltage when the primary current is zero. The ideal value of $V_{\rm o}$ is $U_{\rm c}/2$. So, the difference of $V_{\rm o}$ - $U_c/2$ is called the total offset voltage error. This offset error can be attributed to the electrical offset (due to the resolution of the ASIC quiescent voltage trimming), the magnetic offset, the thermal drift and the thermal hysteresis. Deeper and detailed info available is our LEM technical sales offices (www.lem. com).



Environmental test specifications:

Refer to LEM GROUP test plan laboratory CO.11.11.515.0 with "Tracking_Test Plan_Auto" sheet.

Name	Standard					
CHARACTERIZATION @ 25 °C						
Sensitivity / Accuracy / Overall accuracy	LEM 98.20.00.574.0					
Offset / Electrical Offset / Magnetic Offset	LEM 98.20.00.573.0					
Linearity error	LEM 98.20.00.370.0					
Current Consumption	LEM 98.20.00.579.0					
CHARACTERIZATION	WITH T °C (initial)					
Sensitivity / Accuracy / Overall accuracy	LEM 98.20.00.574.0					
T °C variation of / Temperature Coefficient of G	LEM 98.20.00.574.0					
Offset / Electrical Offset / Magnetic Offset	LEM 98.20.00.573.0					
T °C variation of /Temperature Coefficient of Offset	LEM 98.20.00.573.0					
Linearity error	LEM 98.20.00.370.0					
Current Consumption	LEM 98.20.00.579.0					
ELECTRICAL TI	ESTS @ 25 °C					
Dielectric withstand Voltage test	2500 V AC / 1 min / 50 Hz					
Insulation resistance test	500 V DC , time = 60 s $R_{\text{insulation}} >= 500 \text{ M}\Omega \text{ Minimum}$					
ENVIRONMENTAL T	ENVIRONMENTAL TESTS (CLIMATIC)					
Thermal shock	IEC 60068-2-14 Na (01/2009)					
Steady state T°C Humidity bias life test	JESD 22-A101 (03/2009)					
MECHANICAL TESTS						
Vibration random in T°C	IEC 60068-2-64 (02/2008)					
Shocks	IEC 60068-2-27 (02/2008)					
Free Fall (Device not packaged)	IEC 60068-2-31 §5.2: method 1 (05/2008)					
FINAL CHARACTERIZATION						
Characterization @ 25 °C						
Characterization with temperature						